Comparison of two approaches to improve functional BIST fault coverage

Kostin, Sergei; **Ubar, Raimund-Johannes**; **Gorev, Maksim**; **Mägi, Gunnar** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 105-108 : ill